

(11) Publication number:

10313128 A

Generated Document,

## PATENT ABSTRACTS OF JAPAN

(21) Application number: 09139440

(51) Intl. Cl.: H01L 31/04 C30B 33/12 H01L 21/306

(22) Application date: 13.05.97

(30) Priority:

(43) Date of application publication:

24.11.98

(84) Designated contracting states:

(71) Applicant: MATSUSHITA ELECTRIC IND CO LTD

(72) Inventor: KIM HANMIN
SHIBUYA MUNEHIRO
YOSHIDA TETSUHISA
KITAGAWA MASATOSHI

(74) Representative:

## (54) ANISOTROPICALLY ETCHING METHOD FOR SILICON SUBSTRATE AND MANUFACTURE OF SOLAR CELL

## (57) Abstract:

PROBLEM TO BE SOLVED: To deeply form anisotropically etched pits into an Si substrate surface by introducing an etching gas conc. at least either CIF3 or XeF2 into a reactor chamber at the atmospheric pressure, and etching the substrate surface at specified temp. with this gas to form anisotropically etched pits thereinto.

SOLUTION: A CIF3 gas is fed into a reaction chamber 13 at room temp. and atmospheric pressure, at a rate of 0.2 lit./min. with N2 fed at 2 lit./min. to etch Si 100 and 111 substrate for 2 min. at room temp., thereby forming rectangular and pyramid-like etched pits into the (100)- and (111)-plane substrates. The temp. rise in the structure due to the heat may change the isotropic etching, and hence substrate temp. is suppressed below 130°C. After cooling the substrate, the above steps are repeated to make the anisotropic etching, thus forming a deep irregularities structure. Thus, a substrate having square and pyramid etched pits is formed.

COPYRIGHT: (C)1998,JPO



